

# SUCCESS IS BEING EXCELLENT AT WHAT YOU DO

Learn how to get the most from your PDF-4+ database from the database experts.

Join ICDD at our free PDF-4+ users meeting during the  
58<sup>th</sup> Annual Denver X-ray Conference!

## July Users Meeting

Sunday, 26 July 2009

Denver X-ray Conference 2009

Crowne Plaza Hotel

Colorado Springs, Colorado

10:00 a.m.—4:00 p.m.

*Register by 17 July*

International Centre for Diffraction Data

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## Getting Started Tutorial

This tutorial will discuss and demonstrate the basic functions of DDView+, thus enabling the user to distill the huge number of entries in PDF-4+ to a manageable selected subset.

- ▲ Selecting search criteria for up to 53 unique Search Fields
- ▲ Viewing/analyzing search results
- ▲ Using History and standard formats to optimize your searches
- ▲ Using digital patterns for data simulations and analysis

## Advanced Features Tutorial

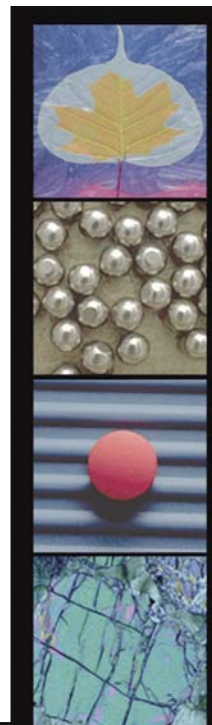
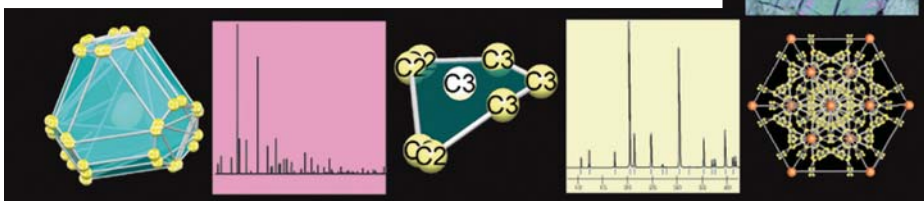
This tutorial focuses on the power of DDView+ and Sieve+ for phase identification, simulation of X-ray, neutron, and electron diffraction patterns, and retrieval/use of PDF-4+ database information for advanced analyses.

- ▲ Performing neutron, electron, EBSD, spot pattern simulations
- ▲ Advanced data mining — tools to extract the data you need
- ▲ Using Sieve+ — choosing the appropriate search criteria and strategies for identification and problem analysis
- ▲ Interfaces — Using PDF-4+ information as input for advanced analyses (whole-pattern fitting, structure analysis, molecular visualization, cluster analysis)

## Problem Solving Examples

- ▲ Published solutions to difficult problems using PDF-4+

Register online at [www.icdd.com/education/usersmeeting.asp](http://www.icdd.com/education/usersmeeting.asp)



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# 2009 PDF-4<sup>+</sup> Users Meeting

## Registration Form *July Users Meeting*

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Crowne Plaza Hotel  
Colorado Springs, Colorado  
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### 3 Easy Ways to Register



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**Please choose up to three topics. We will focus our time on the most requested topics.**

#### **Getting Started Tutorial**

- Selecting search criteria for up to 53 unique Search Fields
- Viewing/analyzing search results
- Using History and standard formats to optimize your searches
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#### **Advanced Features Tutorial**

- Performing neutron, electron, EBSD, spot pattern simulations
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#### **Problem Solving Examples**

- Published solutions to difficult problems using PDF-4 +

#### **Which ICDD products are you currently using?**

- |                                     |                    |   |                    |
|-------------------------------------|--------------------|---|--------------------|
| <input type="checkbox"/> PDF-2      | Release Year _____ | <input type="checkbox"/> PDF-4 +        | Release Year _____ |
| <input type="checkbox"/> DDView     | Release Year _____ | <input type="checkbox"/> PDF-4/Organics | Release Year _____ |
| <input type="checkbox"/> ICDD SUITE | Release Year _____ | <input type="checkbox"/> Sleeve +       | Release Year _____ |

Interests (please circle):

XRD	Corrosion	Minerals	Synchrotron
XRF	Electron Diffraction	Pharmaceutical	Other (please specify):
Alloys	Metals	Semiconductors	